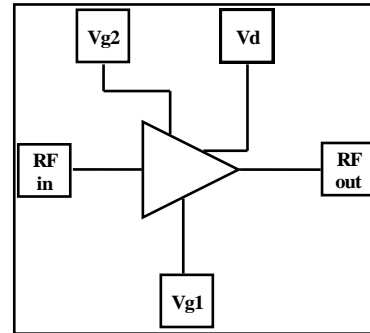


## 2 – 40 GHz Ultra-Wideband Amplifier

### Features

- ◆ Frequency Range: 2-40 GHz
- ◆  $7 \pm 1.0$  dB Nominal Gain
- ◆ Input Return Loss > 10 dB
- ◆ Output Return Loss > 10 dB
- ◆ Reverse Isolation > 30dB
- ◆ 5 dBm Nominal P1dB
- ◆ DC decoupled Input & Output
- ◆ 0.15-um InGaAs pHEMT Technology
- ◆ Chip Size : 3.0 mm x 1.5 mm x 0.1 mm

Functional Diagram



### Typical Applications

- ◆ Wideband LNA/Gain block
- ◆ Electronic warfare
- ◆ Test Instrumentation

### Description

The ASL5007 is an Ultra wideband pHEMT GaAs MMIC designed to operate over 2.0 GHz to 40.0 GHz frequency range. The design employs a 7-stage, cascode-connected pHEMT structure to ensure flat gain and good return loss. The device offers a typical small signal gain of 7 dB over the operating frequency band and has a Noise figure of less than 7.2 dB in entire band. The Input & output are matched to  $50\Omega$  with a VSWR better than 2:1. The chip is unconditionally stable.

The ASL5007 is suitable for a variety of wideband electronic warfare systems such as radar warning receivers, jammers and instrumentation. In addition, the chip may also be used as a gain block. The die is fabricated using a reliable 0.15 $\mu$ m InGaAs pHEMT technology.

### Absolute Maximum Ratings <sup>(1)</sup>

Parameter	Absolute Maximum	Units
Positive DC Supply	8	V
RF Input Power	20	dBm
Supply current	150	mA
Operating Temperature	-55 to +85	°C
Storage Temperature	-65 to +150	°C

1. Operation beyond these limits may cause permanent damage to the component

**Electrical Specifications <sup>(1)</sup> @ T<sub>A</sub> = 25°C, Z<sub>o</sub> =50 Ω, V<sub>d</sub> = 6.0V, V<sub>g2</sub> = 2.0 V, V<sub>g1</sub> =-0.20V**

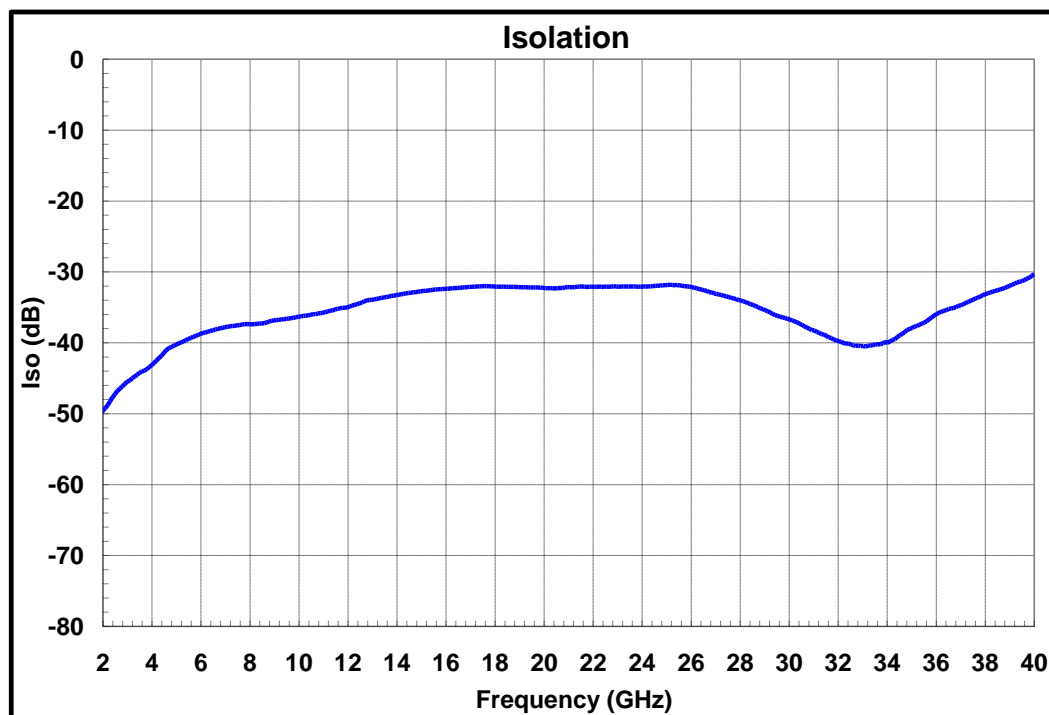
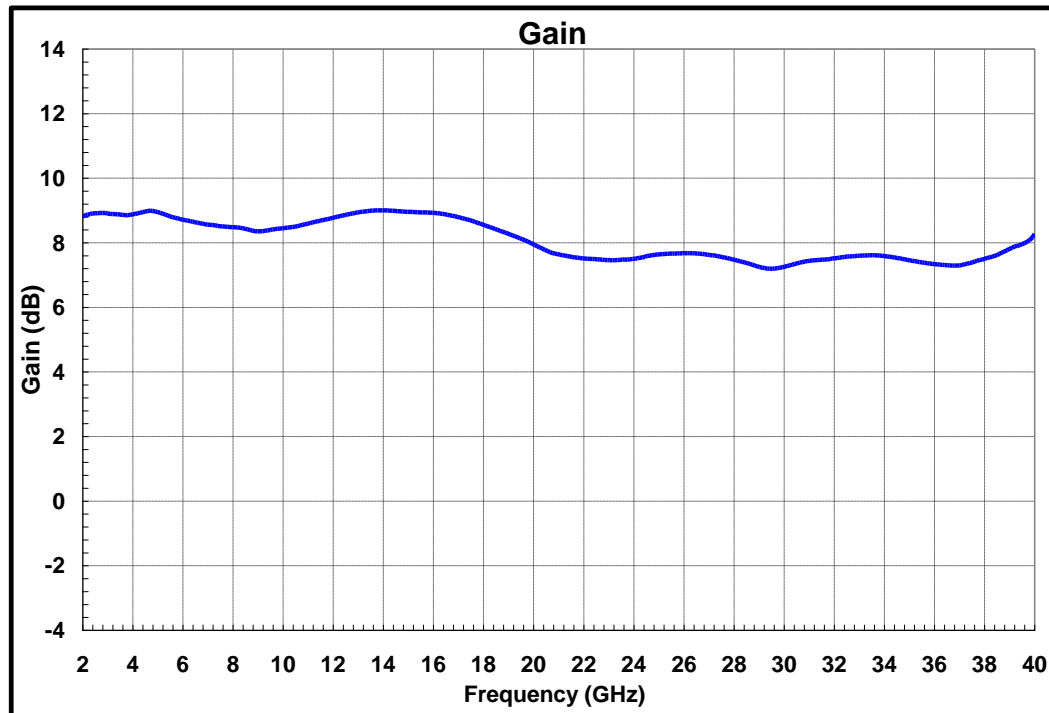
Parameter	Min.	Typ.	Max.	Units
Frequency	2.0	-	40.0	GHz
Gain	6.0	7	8.5	dB
Gain Flatness	-	±0.75	-	dB
Noise Figure	-	5.0	-	dB
Input Return Loss	10	12	-	dB
Output Return Loss	10	12	-	dB
Output Power (P1dB)	-	5	-	dBm
Output Third Order Intercept(IP3)	-	15	-	dBm
Supply Current	-	55	90	mA

**Note:**

1. Electrical specifications mentioned above are measured in a test fixture.
2. For optimal performance, the gate voltage V<sub>g1</sub> should be tuned to achieve a drain current of 55mA (typ.).
3. The negative gate supply (V<sub>g1</sub>) can be tuned from 0V to -0.35V.
4. By varying the V<sub>g1</sub>, the gain & current can be controlled to the user requirements.

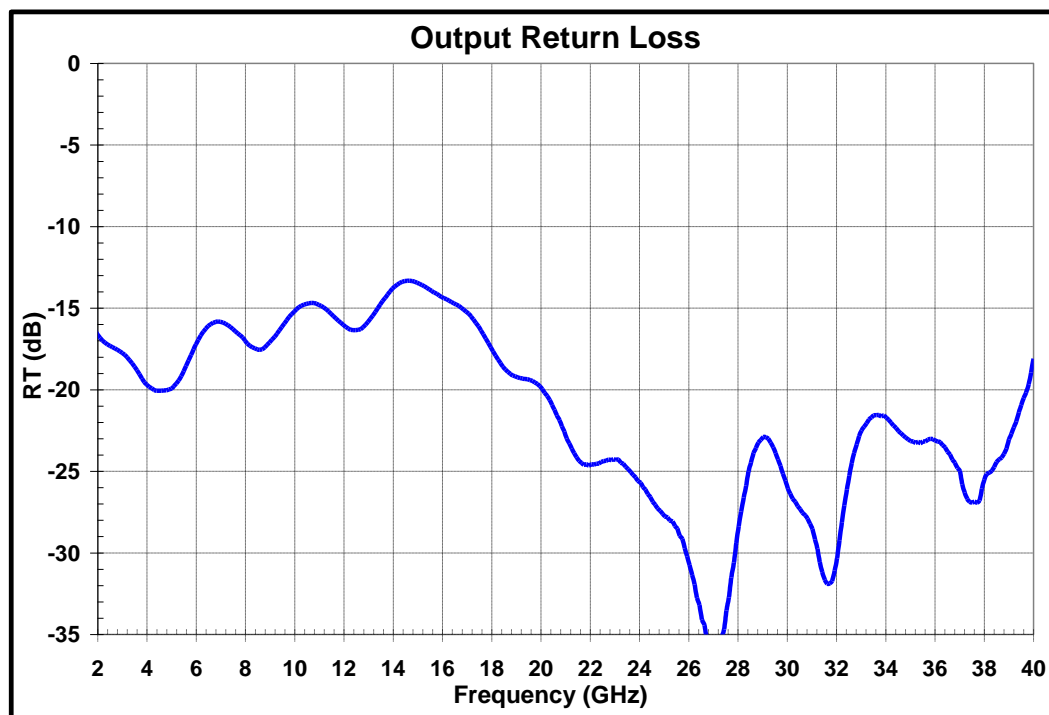
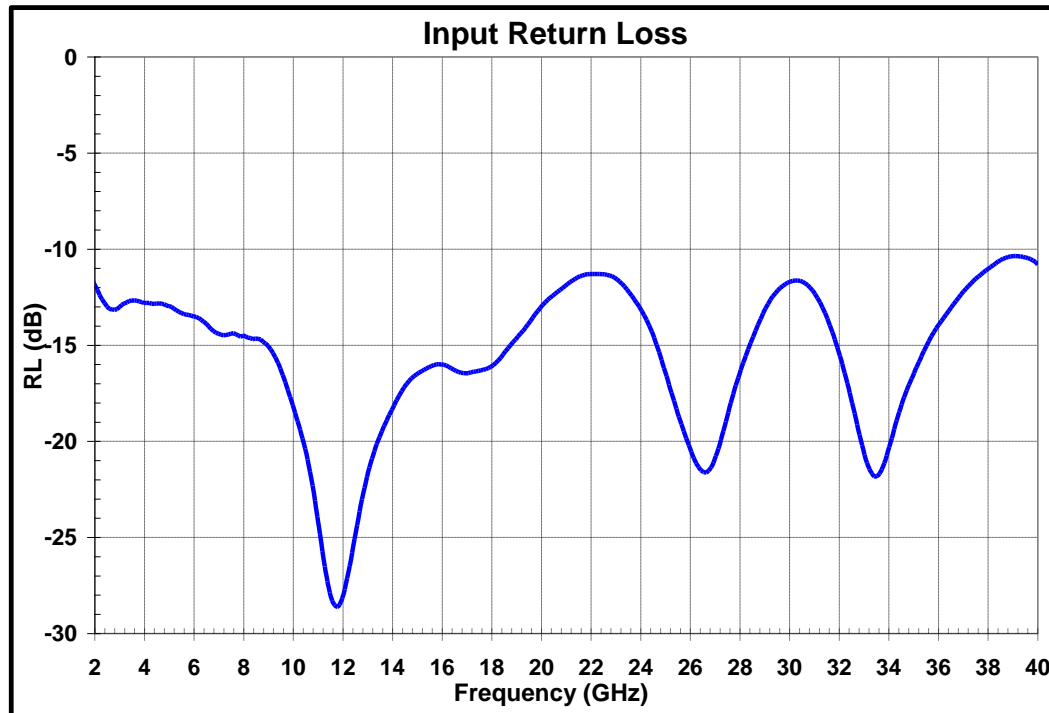
**Test fixture data**

$V_d = +6.0V$ ,  $V_{g2} = +2.0V$  &  $V_{g1} = -0.2V$ , Current = 55 mA,  $T_A = 25^\circ C$

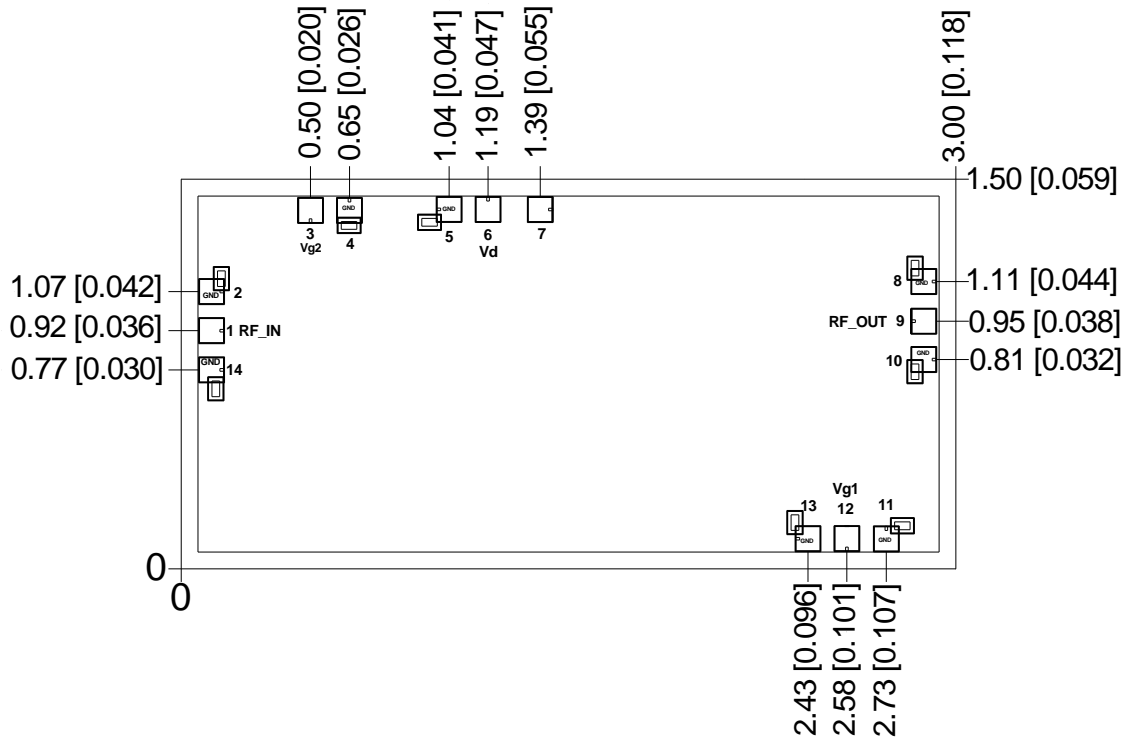


### Test fixture data

$V_d = +6.0V$ ,  $V_{g2} = +2.0V$  &  $V_{g1} = -0.20V$ , Current = 55 mA,  $T_A = 25^\circ C$



## Mechanical Characteristics

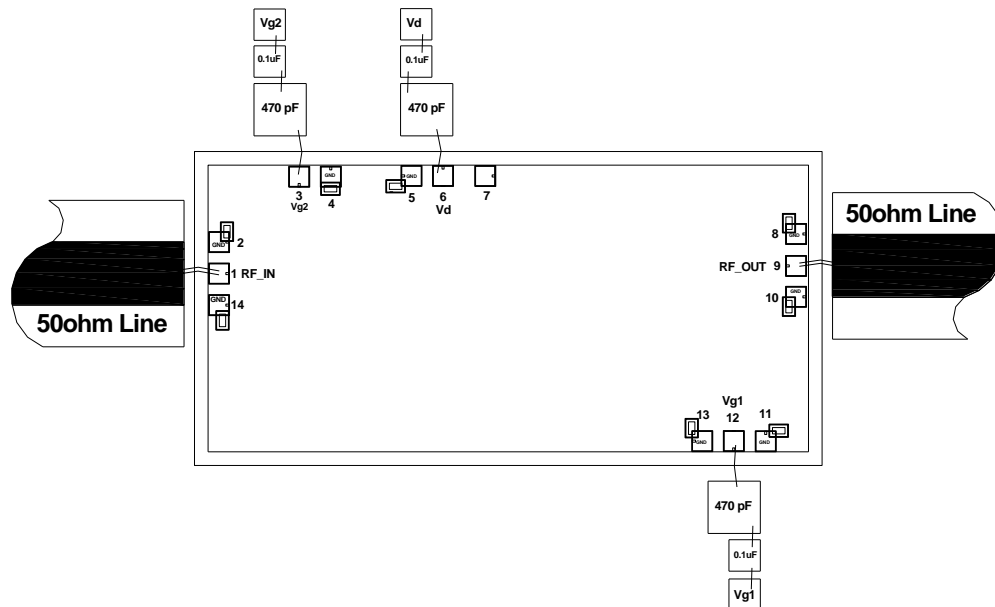


**Units:** millimeters (inches)

**Note:**

1. All RF and DC bond pads are 100µm x 100µm
2. Pad no. 1 : RF In
3. Pad no. 9: RF out
4. Pad no. 6: Vd
5. Pad no.12: Vg1
6. Pad no. 3: Vg2

## Recommended Assembly Diagram



### Note :

1. Two 1 mil (0.0254mm) bond wires of minimum length should be used for RF input and output.
2. Two 1 mil (0.0254mm) bond wires of minimum length should be used from chip bond pad to 470pF capacitor.
3. Input and output 50 ohm lines are on 5 mil RT Duroid substrate
4. 0.1  $\mu$ F capacitors may be additionally used as a second level of bypass for reliable operation
5. The RF input & output ports are DC decoupled on-chip.

**Die attach:** For Epoxy attachment, use of a two-component conductive epoxy is recommended. An epoxy fillet should be visible around the total die periphery. If Eutectic attachment is preferred, use of fluxless AuSn (80/20) 1-2 mil thick preform solder is recommended. Use of AuGe preform should be strictly avoided.

**Wire bonding:** For DC pad connections use either ball or wedge bonds. For best RF performance, use of 150 - 200 $\mu$ m length of wedge bonds is advised. Single Ball bonds of 250-300 $\mu$ m though acceptable, may cause a deviation in RF performance.



**GaAs MMIC devices are susceptible to Electrostatic discharge. Proper precautions should be observed during handling, assembly & testing**

All information and Specifications are subject to change without prior notice